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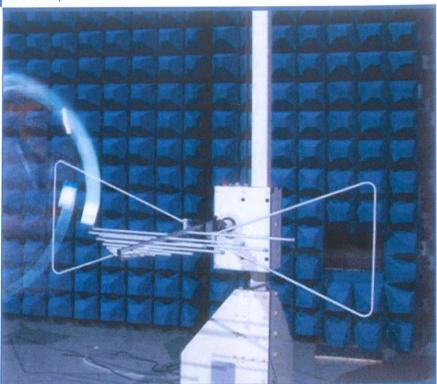


FOR

X1 FDD-LTE Smartphone

ISSUED TO TP-LINK Technologies Co., Ltd.

Building 24-1F/3F/4F/5F, 28-1F/2F/3F/4F Science and Technology Park, Shennan Road, Nanshan District, Shenzhen City, Guangdong Province, P. R. China



Tested by: Xia Long
(Engineer)
Date May 15 2017

Approved by:
Liao Jianming
(Technical Director)
Date May 15.217

Report No.:

BL-SZ1720179-402

EUT Name: X1 FDD-LTE Smartphone

Model Name: TP902C

Brand Name: neffos

Test Standard: 47 CFR

FCC ID:

Helios

47 CFR Part 15 Subpart B

TE7X1V1

Test Conclusion:

Test Date:

Pass

Test Date:

Apr. 10, 2017 ~ May 14, 2017

Date of Issue: May 15, 2017

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Revision History

VersionIssue DateRevisions ContentRev. 01Apr. 21, 2017Initial Issue

Rev. 02 May 15, 2017 Increa

Increases the relevance description with the report BL-SZ1720179-401, retest the USB mode and update the data

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1 GENERAL INFORMATION

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Addross	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi
Address	Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.	
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi	
Address	Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China	
	The laboratory has been listed by Industry Canada to perform	
	electromagnetic emission measurements. The recognition numbers	
	of test site are 11524A-1.	
Approditation	The laboratory has been listed by US Federal Communications	
Accreditation	Commission to perform electromagnetic emission measurements.	
Certificate	The recognition numbers of test site are 832625.	
	The laboratory is a testing organization accredited by China National	
	Accreditation Service for Conformity Assessment (CNAS) according	
	to ISO/IEC 17025. The accreditation certificate number is L6791.	
	All measurement facilities used to collect the measurement data are	
Description	located at Block B, FL 1, Baisha Science and Technology Park, Shahe	
Description	Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R.	
	China 518055	

1.3 Laboratory Condition

Ambient Temperature	20°C~25°C
Ambient Relative Humidity	45% - 55%
Ambient Pressure	100 kPa - 102 kPa

1.4 Announce

- (1) The test report reference to the report template version v6.4.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (5) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (6) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	TP-LINK Technologies Co., Ltd.
	Building 24-1F/3F/4F/5F, 28-1F/2F/3F/4F Science and Technology
Address	Park, Shennan Road, Nanshan District, Shenzhen City,
	Guangdong Province, P. R. China

2.2 Manufacturer Information

Manufacturer	TP-LINK Technologies Co., Ltd.
	Building 24-1F/3F/4F/5F, 28-1F/2F/3F/4F Science and Technology
Address	Park, Shennan Road, Nanshan District, Shenzhen City,
	Guangdong Province, P. R. China

2.3 Factory Information

Factory	N/A
Address	N/A

2.4 General Description for Equipment under Test (EUT)

EUT Name	V1 EDD LTE Smartphone	
	X1 FDD-LTE Smartphone	
Model Name Under Test	TP902C	
Series Model Name	TP902C, TP902CXYZZ	
Description of Model	X=2 or 4 (2 indicates Cloudy Grey, 4 indicates Sunrise Gold);	
name differentiation	Y=4 or 6 (4 indicates the memory is 2G RAM + 16G Flash, 6	
	indicates the memory is 3G RAM + 32G Flash);	
	ZZ indicates different national.	
Hardware Version	N/A	
Software Version	N/A	
Dimensions (Approx.)	N/A	
Weight (Approx.)	N/A	
Random-access	OC DAM + 400 Floor	
Memory	2G RAM + 16G Flash	
Network and Wireless	2G Network GSM/GPRS/EDGE 850/1900 MHz	
connectivity	3G Network WCDMA/HSDPA/HSUPA Band 2/4/5	
	4G Network FDD LTE Band 2/4/7	
	Bluetooth, WIFI, FM, GPS, GLONASS	



2.5 Ancillary Equipment

	Battery	
	Brand Name	neffos
	Model No.	NBL-38A2250
Ancillary Equipment 1	Serial No.	N/A
	Capacitance	2020 mAh
	Rated Voltage	3.85 V
	Limit Charge Voltage	4.4 V
	Charger	
	Brand Name	neffos
Ancillary Equipment 2	Model Name	N050100-2B3
	Rated Input	100-240 V ~, 50/60 Hz, 300 mA
	Rated Output	5 V =, 1 A
Ancillary Equipment 3	Earphone	
Andmary Equipment 3	Length(Approx.)	95 cm
Ancillary Equipment 4	USB Cable	
Ancillary Equipment 4	Length(Approx.)	100 cm

2.6 Technical Information

The requirement for the following technical information of the EUT was tested in this report:

•	9	· ·
	The Highest Speed of	1.3 GHz
	Processor	1.5 0112



3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title	
1	FCC 47 CFR Part 15	Unintentional Radiators	
ı	Subpart B (10-1-15 Edition)	Onintentional Radiators	
	ANSI C63.4-2014	American National Standard for Methods of	
		Measurement of Radio-Noise Emissions from Low-	
2		Voltage Electrical and Electronic Equipment in the	
		Range of 9 kHz to 40 GHz	

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Result
1	Radiated Emission	15.109	Pass	Annex A .1
2	Conducted Emission, AC Ports	15.107	Pass	Annex A .2

Note: Because of the EUT and the test sample (which in the test report No. is BL-SZ1720179-401, and it issued by Shenzhen BALUN Technology Co., Ltd. On May 15, 2017) just have the different memory version. The other hardware circuit all the same. So all of the test items please refer to the report BL-SZ1720179-401 (issued by Shenzhen BALUN Technology Co., Ltd. On May 15, 2017 and only evaluated Radiated Emission below 1GHz).

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9 kHz-30 MHz)	3.23 dB
Radiated emissions (30 MHz-1 GHz)	4.30 dB
Radiated emissions (1 GHz-18 GHz)	4.81 dB
Radiated emissions (18 GHz-40 GHz)	5.71 dB



4 GENERAL TEST CONFIGURATIONS

4.1 Test Environments

Environment	Selected Values During Tests				
Parameter	Temperature	Voltage	Relative Humidity	Ambient Pressure	
Normal Temperature,					
Normal Voltage	23°C~26°C	AC 120 V/60 Hz	50%-55%	100 to 102 kPa	
(NTNV)					

4.2 Test Equipment List

	Radiated Emission Test For Frequency Below 1 GHz					
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWA	ESRP	101036	2016.07.05	2017.07.04	\boxtimes
LIVII I (COCIVCI	RZ	Loru	101000	2010.07.00	2017.07.04	
Test Antenna-	SCHWARZBECK	VULB 9163	9163-977	2016.07.19	2018.07.18	\boxtimes
Bi-Log	OOHWARZBLOK	VOLD 9103	0100 077	2010.07.10	2010.07.10	
Test Antenna-	SCHWARZBECK	BBHA	9120D-1600	2016.07.12	2018.07.11	
Horn	SCHWARZBECK	9120D	91200-1000	2010.07.12	2016.07.11	
Anechoic	EMC Electronic	20.10*11.60	N/A	2016.08.09	2018.08.08	\boxtimes
Chamber	Co., Ltd	*7.35m	IN/A	2010.00.09	2010.00.00	

	Radiated Emission Test For Frequency Above 1 GHz					
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9038A	MY53220118	2016.09.09	2017.09.08	\boxtimes
Test Antenna-	SCHWARZBECK	VULB 9163	9163-624	2015.07.22	2017.07.21	
Bi-Log	GCHWARZBECK	VOLD 9103	3103-024	2010.07.22	2017.07.21	
Test Antenna-	SCHWARZBECK	BBHA	9120D-1148	2015.07.22	2017.07.21	\boxtimes
Horn	SCHWARZBECK	9120D	91200-1146	2015.07.22	2017.07.21	
Anechoic	RAINFORD	9m*6m*6m	N/A	2017.02.21	2019.02.20	\boxtimes
Chamber	RAINFORD	וווס וווס ווופ	IN/A	2017.02.21	2019.02.20	

Conducted Emission Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWA RZ	ESRP	101036	2016.07.05	2017.07.04	\boxtimes
LISN	SCHWARZBECK	NSLK 8127	8127-687	2016.07.05	2017.07.04	\boxtimes
LISN	SCHWARZBECK	NNLK 8129	8129-462	2016.09.14	2017.09.13	
AMN	SCHWARZBECK	NNBM8124	8124-509	2016.07.05	2017.07.04	
AMN	SCHWARZBECK	NNBM8124	8124-510	2016.07.05	2017.07.04	
ISN	TESEQ	ISN T800	34449	2016.07.05	2017.07.04	
Shielded Enclosure	ChangNing	CN-130701	130703	N/A	N/A	\boxtimes



4.3 Test Enclosure list

Description	Manufacturer	Model	Serial No.	Length	Description	Use
PC	Dell	015K3N	N/A	N/A	Special Handled	\boxtimes
Laptop	Apple	A1465	N/A	N/A	N/A	
Printer	HP	DESKJET 1000	N/A	N/A	N/A	\boxtimes
Keyboard	Dell	N/A	N/A	N/A	N/A	\boxtimes
Mouse	Dell	N/A	N/A	N/A	N/A	\boxtimes
USB disk	Kingston	N/A	N/A	N/A	N/A	
TF Card	Kingston	N/A	N/A	N/A	N/A	\boxtimes
VGA Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
HDMI Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
DVI Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
Coaxial video cable	N/A	N/A	N/A	2.0 m	Shielded with core	
iPhone	Apple	A1586	N/A	N/A	N/A	
Phone	MI	M4	N/A	N/A	N/A	
Bluetooth Earphone	SAMSUNG	Gear Circle	N/A	N/A	N/A	\boxtimes
GPS/GLONAS S Vector signal generator	R&S	N5172B EXG	N/A	N/A	N/A	\boxtimes
WIFI Router	TP-LINK	TL-WDR7500	N/A	N/A	N/A	\boxtimes
Earphone	N/A	OPPO	N/A	1.1 m	N/A	
Car Battery	Camel	55530	N/A	N/A	12 V/55 Ah	
Artificial load	N/A	N/A	N/A	N/A	2.5 Ω/100 W	
Artificial load	N/A	N/A	N/A	N/A	5 Ω/100 W	
Electronic Load	ITECH	IT8511	N/A	N/A	N/A	
USB Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
DC Power Supply	ITECH	IT6863A	60001401068 7210006	N/A	N/A	
LCD Monitor	SAMSUNG	UA32C4000P	N/A	N/A	N/A	
LCD Monitor	Dell	U241HB	N/A	N/A	N/A	
RJ45 Cable	N/A	N/A	N/A	1.5 m	Shielded with core	



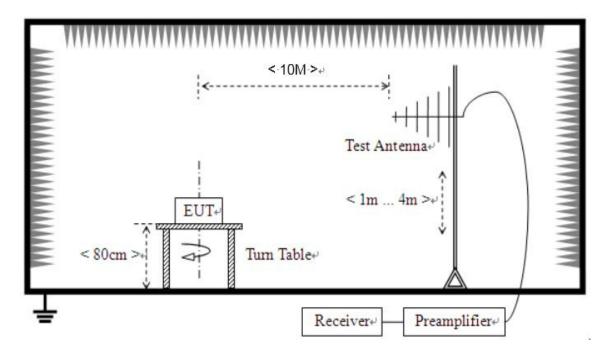
4.4 Test Configurations

Test	
Configurations	Description
(TC) No.	
Traffic Test Mod	e
	The GSM 850 MHz Test Mode
TC01	GSM 850 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GLONASS RX
	The EDGE 850 MHz Test Mode
TC02	EDGE 850 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GPS RX
	The GSM 1900 Test Mode
TC03	GSM 1900 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GPS RX
	The EDGE 1900 MHz Test Mode
TC04	EDGE 1900 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GLONASS RX
	The WCDMA Band 2 Test Mode
TC05	WCDMA Band 2 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GLONASS RX
	The WCDMA Band 4 test mode
TC06	WCDMA Band 4 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GPS RX
	The WCDMA Band 5 test mode
TC07	WCDMA Band 5 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GPS RX
	The FDD LTE Band 2 Test Mode
TC08	LTE Band 2 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link +
	GLONASS RX
	The FDD LTE Band 4 Test Mode
TC09	LTE Band 4 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link+
	GPS RX
	The FDD LTE Band 7 Test Mode
TC10	LTE Band 7 Link + Adapter + USB Cable + Battery + Earphone + BT Link + WIFI Link+
	GLONASS RX
TC11	The Idle Test Mode
	GSM 850(Idle) + Battery + Adapter + USB Cable + Earphone + FM RX
Amusement Tes	
TC12	The Download Test Mode
	EUT + USB Cable + Battery + Earphone + TF Card + PC + Printer + Keyboard + Mouse
TC13	The Video Record Test Mode
	EUT + Adapter + USB Cable + Battery + Earphone + TF Card
TC14	The Video Play Test Mode
	EUT + Adapter + USB Cable + Battery + Earphone + TF Card



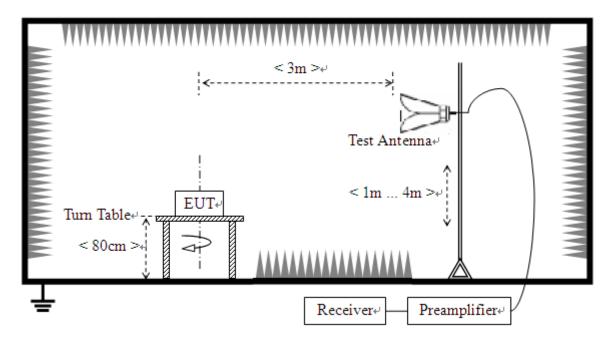
4.5 Test Setups

Test Setup 1



(For Radiated Emission Test (30 MHz-1 GHz))

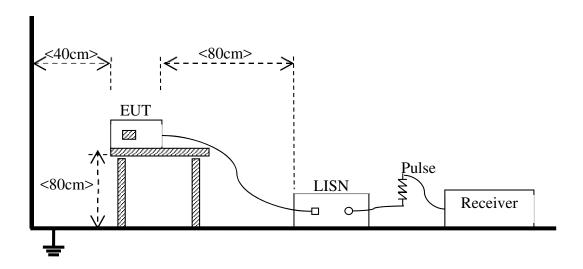
Test Setup 2



(For Radiated Emission Test (above 1 GHz))



Test Setup 3



(For Conducted Emission, AC Ports Test)



4.6 Test Conditions

Test Case	Test Conditions		
	Test Env.	NTNV	
Radiated Emission	Test Setup	Test Setup 1&2	
	Test Configuration	TC01~TC14 Note	
Conducted Emission AC	Test Env.	NTNV	
Conducted Emission, AC	Test Setup	Test Setup 3	
Ports	Test Configuration	TC01~TC14 Note	

Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report. The GSM 850 MHz test mode is the worst mode in this report.



5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Eroguanov rango	Class B	(at 3 m)	Class A (at 10 m)		
Frequency range	Field Strength	Field Strength	Field Strength	Field Strength	
(MHz)	(μV/m)	(dBµV/m)	(μV/m)	(dBµV/m)	
30 - 88	100	40	90	39	
88 - 216	150	43.5	150	43.5	
216 - 960	200	46	210	46.4	
Above 960	500	54	300	49.5	

NOTE:

- 1) Field Strength ($dB\mu V/m$) = 20*log [Field Strength ($\mu V/m$)].
- 2) In the emission tables above, the tighter limit applies at the band edges.

5.1.1.2 Test Setup

Refer to 4.5 section (test setup 1 to test setup 2) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

5.1.1.4 Test Result

Please refer to ANNEX A.1.



5.1.2 Conducted Emission

5.1.2.1 Test Limit

	Class A		
Frequency range (MHz)	Quasi-peak	Average	
	(dBµV)	(dBµV)	
0.15 - 0.50	79	66	
0.50 - 30	73	60	

	Cla	ass B
Frequency range (MHz)	Quasi-peak	Average
	(dBµV)	(dBµV)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.5 section test (test setup 3) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides $50 \Omega/50 \mu H$ of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

5.1.2.4 Test Result

Please refer to ANNEX A.2.



ANNEX A TEST RESULTS

A.1 Radiated Emission

Note 1: The symbol of "--" in the table which means not application.

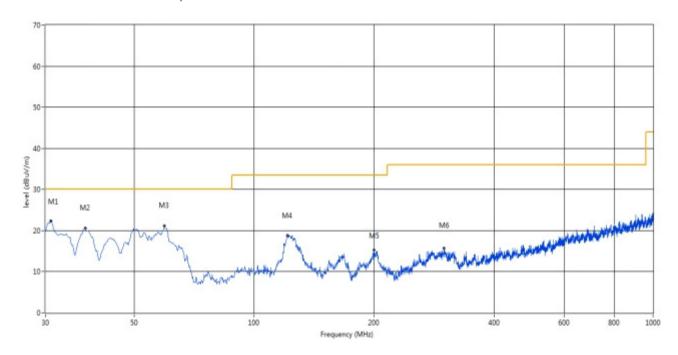
Note 2: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Note 3: This frequency which near 850 MHz with circle should be ignored because they are MS and SS carrier frequency, the marked spikes near 2400 MHz with circle should be ignored because they are Bluetooth or WIFI carrier frequency.

Test Data and Plots

The GSM 850 MHz Test Mode

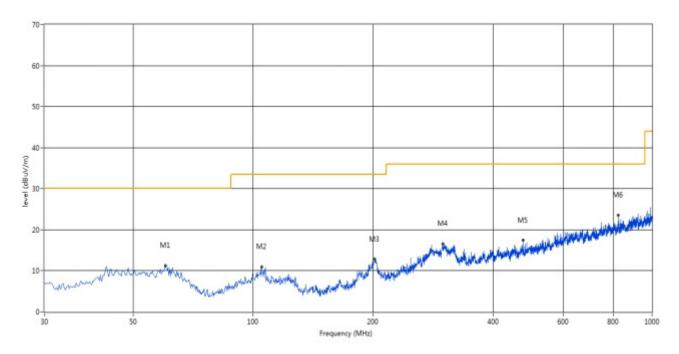
A.1.1 Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	30.970	22.35	-16.82	30.0	7.65	Peak	68.00	100	Vertical	Pass
2	37.758	20.63	-15.03	30.0	9.37	Peak	212.00	100	Vertical	Pass
3	59.578	21.15	-14.95	30.0	8.85	Peak	51.00	100	Vertical	Pass
4	121.400	18.74	-17.34	33.5	14.76	Peak	0.00	200	Vertical	Pass
5	199.708	15.29	-15.05	33.5	18.21	Peak	345.00	100	Vertical	Pass
6	299.350	15.63	-12.31	36.0	20.37	Peak	253.00	100	Vertical	Pass



A.1.2 Test Antenna Horizontal, 30 MHz – 1 GHz



No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	60.305	11.27	-15.06	30.0	18.73	Peak	347.00	400	Horizontal	Pass
2	105.156	10.95	-15.02	33.5	22.55	Peak	138.00	200	Horizontal	Pass
3	201.647	12.81	-15.03	33.5	20.69	Peak	63.00	400	Horizontal	Pass
4	299.108	16.54	-12.32	36.0	19.46	Peak	73.00	400	Horizontal	Pass
5	474.876	17.41	-8.31	36.0	18.59	Peak	0.00	200	Horizontal	Pass
6	823.504	23.54	-2.05	36.0	12.46	Peak	304.00	300	Horizontal	Pass



Test Data and Plots (Above 1 GHz)

A.1.3 Test Antenna Vertical, 1 GHz – 6 GHz

Note: Test Data and Plots (Above 1 GHz) result reference from original test report: BL-SZ1720179-401 (issued by Shenzhen BALUN Technology Co., Ltd. On May 15, 2017) A.1.3 Test Antenna Vertical, 1 GHz - 6 GHz



A.1.4 Test Antenna Horizontal, 1 GHz – 6 GHz

Note: Test Data and Plots (Above 1 GHz) result reference from original test report: BL-SZ1720179-401 (issued by Shenzhen BALUN Technology Co., Ltd. On May 15, 2017) A.1.4 Test Antenna Horizontal, 1 GHz - 6 GHz

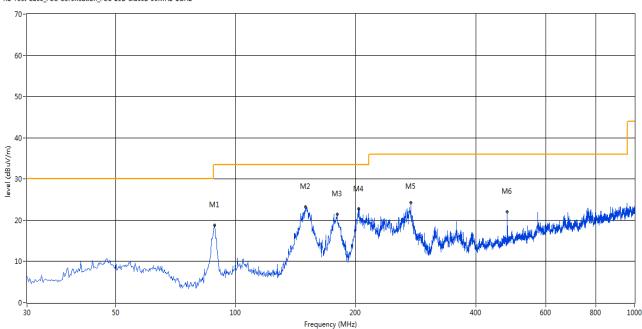


Test Data and Plots

The USB Test Mode

A.1.5 Test Antenna Vertical, 30 MHz – 1 GHz

RE Test Case_FCC Certification_FCC 15B ClassB 30MHz-1GHz

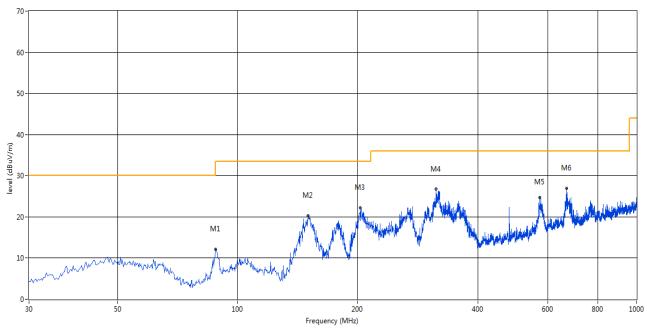


No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	88.670	18.77	-17.45	33.5	14.73	Peak	0.00	200	Vertical	Pass
2	149.523	23.19	-18.71	33.5	10.31	Peak	3.00	100	Vertical	Pass
3	179.585	21.51	-16.96	33.5	11.99	Peak	99.00	100	Vertical	Pass
4	203.829	22.73	-14.92	33.5	10.77	Peak	0.00	200	Vertical	Pass
5	274.864	24.29	-13.02	36.0	11.71	Peak	229.00	100	Vertical	Pass
6	479.968	22.07	-8.21	36.0	13.93	Peak	273.00	100	Vertical	Pass



A.1.6 Test Antenna Horizontal, 30 MHz – 1 GHz

RE Test Case_FCC Certification_FCC 15B ClassB 30MHz-1GHz



No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	88.185	12.18	-17.58	33.5	21.32	Peak	268.00	400	Horizontal	Pass
2	150.250	20.33	-18.68	33.5	13.17	Peak	251.00	400	Horizontal	Pass
3	202.859	22.25	-14.98	33.5	11.25	Peak	32.00	400	Horizontal	Pass
4	314.139	26.73	-11.95	36.0	9.27	Peak	260.00	300	Horizontal	Pass
5	572.579	24.77	-6.11	36.0	11.23	Peak	42.00	200	Horizontal	Pass
6	668.100	26.92	-4.49	36.0	9.08	Peak	178.00	100	Horizontal	Pass



A.1.7 Test Antenna Vertical, 1 GHz – 6 GHz

Note: Test Data and Plots (Above 1 GHz) result reference from original test report: BL-SZ1720179-401 (issued by Shenzhen BALUN Technology Co., Ltd. On May 15, 2017) A.1.7 Test Antenna Vertical, 1 GHz - 6 GHz



A.1.8 Test Antenna Horizontal, 1 GHz – 6 GHz

Note: Test Data and Plots (Above 1 GHz) result reference from original test report: BL-SZ1720179-401 (issued by Shenzhen BALUN Technology Co., Ltd. On May 15, 2017) A.1.8 Test Antenna Horizontal, 1 GHz - 6 GHz



A.2 Conducted Emission

Note: Conducted Emission Test Data and Plots result reference from original test report: BL-SZ1720179-401 (issued by Shenzhen BALUN Technology Co., Ltd. On May 15, 2017) A.2 Conducted Emission.



ANNEX B TEST SETUP PHOTOS

Please refer the document "BL-SZ1720179-AE.PDF".

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document "BL-SZ1720179-AW.PDF".

ANNEX D EUT INTERNAL PHOTOS

Please refer the document "BL-SZ1720179-AI.PDF".

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